

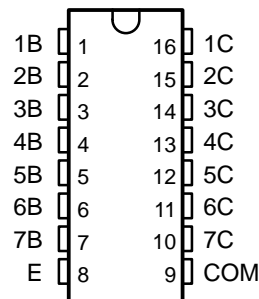
ULQ2003A-Q1, ULQ2004A-Q1, HIGH-VOLTAGE HIGH-CURRENT DARLINGTON TRANSISTOR ARRAY

SGLS148 – DECEMBER 2002

- Qualification in Accordance With AEC-Q100†
- Qualified for Automotive Applications
- Customer-Specific Configuration Control Can Be Supported Along With Major-Change Approval
- ESD Protection Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- 500-mA Rated Collector Current (Single Output)
- High-Voltage Outputs . . . 50 V
- Output Clamp Diodes
- Inputs Compatible With Various Types of Logic
- Relay-Driver Applications

† Contact factory for details. Q100 qualification data available on request.

**D PACKAGE
(TOP VIEW)**



description

The ULQ2003A-Q1 and ULQ2004A-Q1 are high-voltage, high-current Darlington transistor arrays. Each consists of seven npn Darlington pairs that feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of a single Darlington pair is 500 mA. The Darlington pairs can be paralleled for higher current capability. Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers.

The ULQ2003A-Q1 has a 2.7-k Ω series base resistor for each Darlington pair, for operation directly with TTL or 5-V CMOS devices. The ULQ2004A-Q1 has a 10.5-k Ω series base resistor to allow operation directly from CMOS devices that use supply voltages of 6 V to 15 V. The required input current of the ULQ2004A-Q1 is below that of the ULQ2003A-Q1.

AVAILABLE OPTIONS

T _A	D PACKAGES†
	SMALL OUTLINE
–40°C to 105°C	ULQ2003ATDQ1 ULQ2003ATDRQ1
	ULQ2004ATDQ1‡ ULQ2004ATDRQ1‡

† The D package is available taped and reeled. Add the suffix R to device type (e.g., ULQ2003TDADRQ1).

‡ ULQ2004ATDQ1 and ULQ2004ATDRQ1 are Product Preview only.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

This document contains information on products in more than one phase of development. The status of each device is indicated on the page(s) specifying its electrical characteristics.

**TEXAS
INSTRUMENTS**

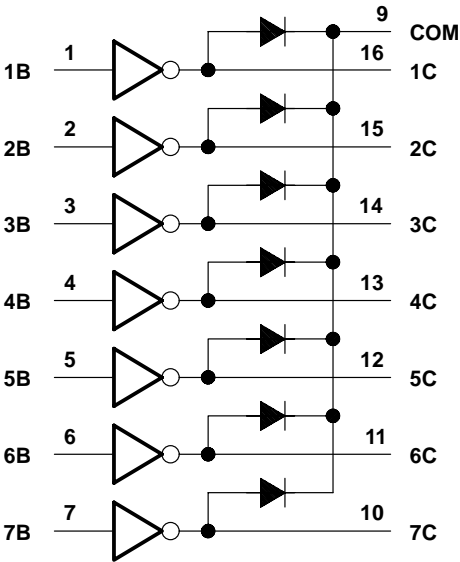
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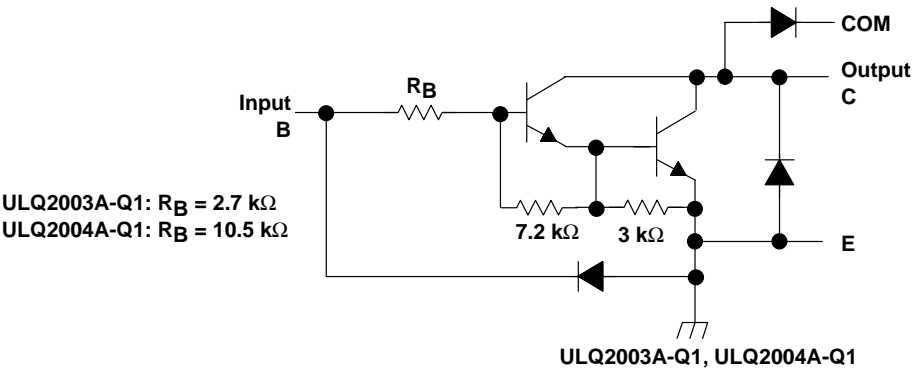
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logic diagram



schematics (each Darlington pair)



All resistor values shown are nominal.

absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)[†]

Collector-emitter voltage	50 V
Clamp diode reverse voltage (see Note 1)	50 V
Input voltage, V_I (see Note 1)	30 V
Peak collector current (see Figure 14)	500 mA
Output clamp current, I_{OK}	500 mA
Total emitter-terminal current	–2.5 A
Continuous total power dissipation	See Dissipation Rating Table
Package thermal impedance, θ_{JA} (see Note 2)	73°C/W
Operating free-air temperature range, T_A	–40°C to 105°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.
 2. The package thermal impedance is calculated in accordance with JESD 51-7.

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DISSIPATION RATING TABLE

PACKAGE	T _A = 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 85°C POWER RATING	T _A = 105°C POWER RATING
D	950 mW	7.6 mW/°C	494 mW	342 mW

electrical characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		ULQ2003A-Q1			ULQ2004A-Q1			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
V _{I(on)}	On-state input voltage, See Figure 6	V _{CE} = 2 V	I _C = 125 mA						5	V
			I _C = 200 mA				2.7		6	
			I _C = 250 mA				2.9			
			I _C = 275 mA						7	
			I _C = 300 mA				3			
			I _C = 350 mA						8	
V _{CE(sat)}	Collector-emitter saturation voltage, See Figure 5	I _I = 250 μA, I _C = 100 mA		0.9	1.2		0.9	1.1	V	
		I _I = 350 μA, I _C = 200 mA		1	1.4		1	1.3		
		I _I = 500 μA, I _C = 350 mA		1.2	1.7		1.2	1.6		
I _{CEX}	Collector cutoff current	V _{CE} = 50 V, I _I = 0, See Figure 1				100		50	μA	
		V _{CE} = 50 V, See Figure 2	I _I = 0				100			
			V _I = 1 V				500			
V _F	Clamp forward voltage, See Figure 8	I _F = 350 mA			1.7	2.2		1.7	2	V
I _{I(off)}	Off-state input current, See Figure 3	V _{CE} = 50 V, I _C = 500 μA		30	65		50	65		μA
I _I	Input current, see Figure 4	V _I = 3.85 V			0.93	1.35				mA
		V _I = 5 V					0.35	0.5		
		V _I = 12 V					1	1.45		
I _R	Clamp reverse current, See Figure 7	V _R = 50 V, T _A = 25°C				100		50		μA
		V _R = 50 V				100		100		
C _i	Input capacitance	V _I = 0, f = 1 MHz			15	25		15	25	pF

switching characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	ULQ2003A-Q1, ULQ2004A-Q1			UNIT
			MIN	TYP	MAX	
tPLH	Propagation delay time, low-to-high level output	See Figure 9	1		10	μs
tPHL	Propagation delay time, high-to-low level output	See Figure 9	1		10	μs
VOH	High-level output voltage after switching	VS = 50 V, IO ≈ 300 mA, See Figure 10	VS-500			mV



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PARAMETER MEASUREMENT INFORMATION

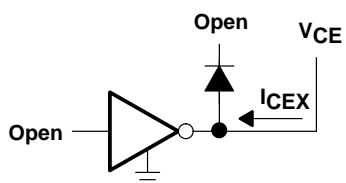


Figure 1. I_{CEX} Test Circuit

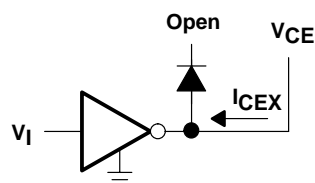


Figure 2. I_{CEX} Test Circuit

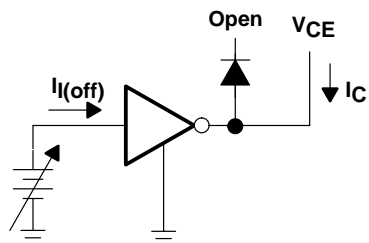


Figure 3. $I_{I(off)}$ Test Circuit

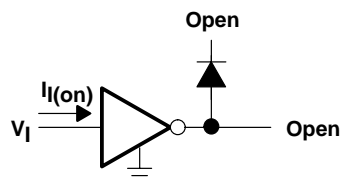
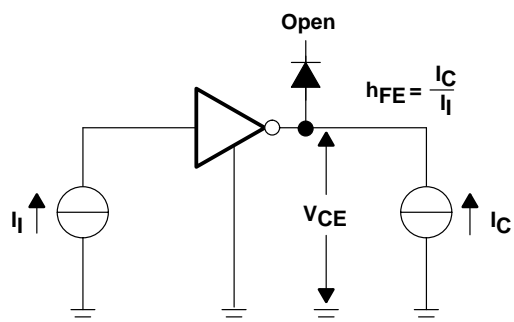


Figure 4. I_I Test Circuit



NOTE: I_I is fixed for measuring $V_{CE(sat)}$, variable for measuring h_{FE} .

Figure 5. h_{FE} , $V_{CE(sat)}$ Test Circuit

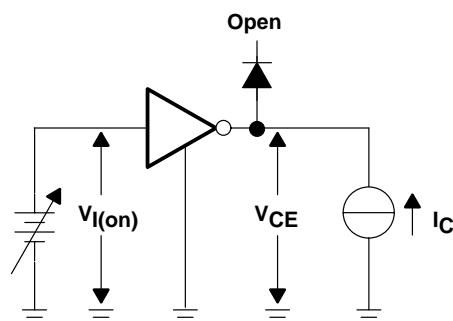


Figure 6. $V_{I(on)}$ Test Circuit

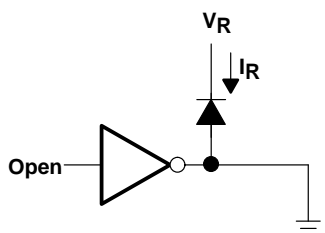


Figure 7. I_R Test Circuit

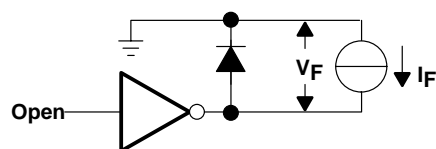


Figure 8. V_F Test Circuit

PARAMETER MEASUREMENT INFORMATION

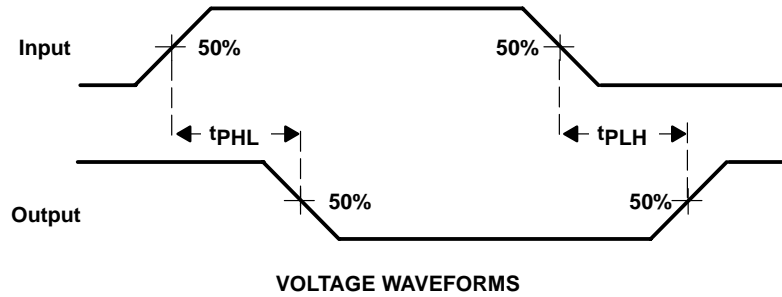
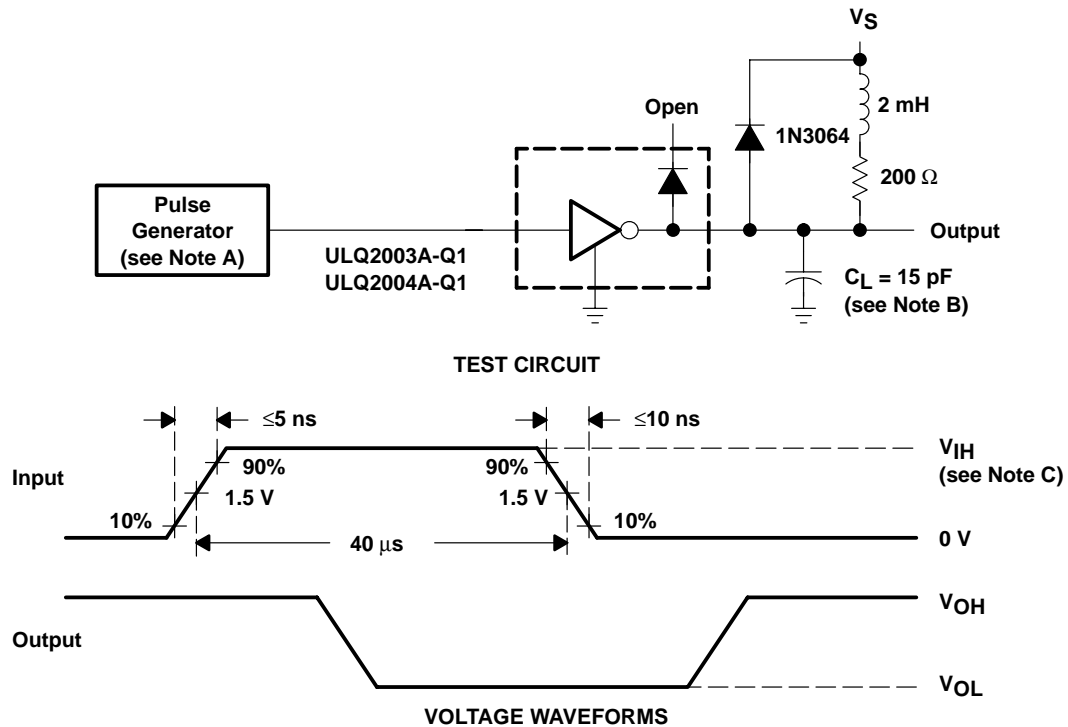


Figure 9. Propagation Delay-Time Waveforms



- NOTES: A. The pulse generator has the following characteristics: PRR = 12.5 kHz, $Z_O = 50 \Omega$.
B. C_L includes probe and jig capacitance.
C. For testing the ULQ2003A-Q1, $V_{IH} = 3 \text{ V}$; for the ULQ2004A-Q1, $V_{IH} = 8 \text{ V}$.

Figure 10. Latch-Up Test Circuit and Voltage Waveforms

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TYPICAL CHARACTERISTICS

COLLECTOR-EMITTER SATURATION VOLTAGE

vs
COLLECTOR CURRENT
(ONE DARLINGTON)

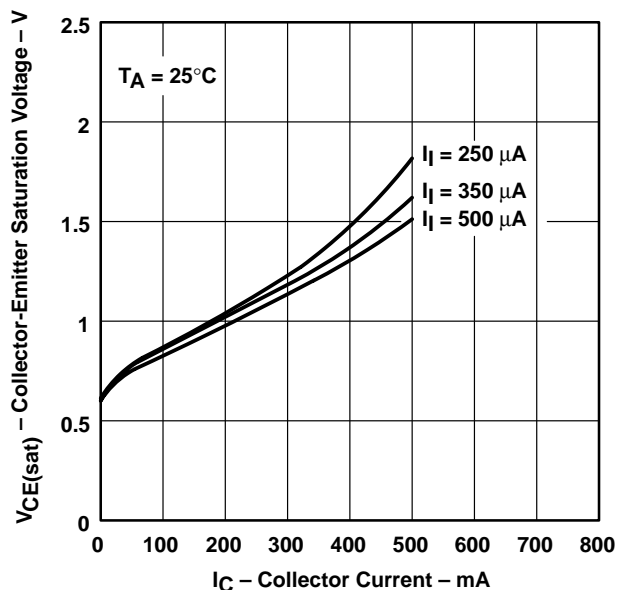


Figure 11

COLLECTOR-EMITTER SATURATION VOLTAGE

vs
TOTAL COLLECTOR CURRENT
(TWO DARLINGTONS IN PARALLEL)

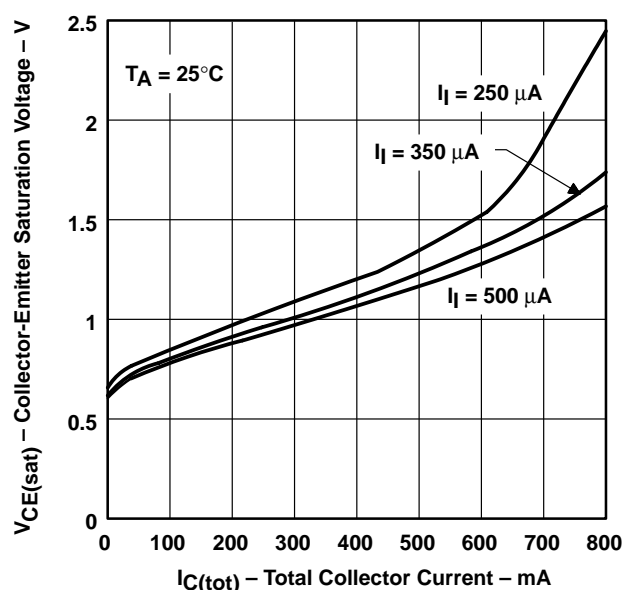


Figure 12

COLLECTOR CURRENT vs INPUT CURRENT

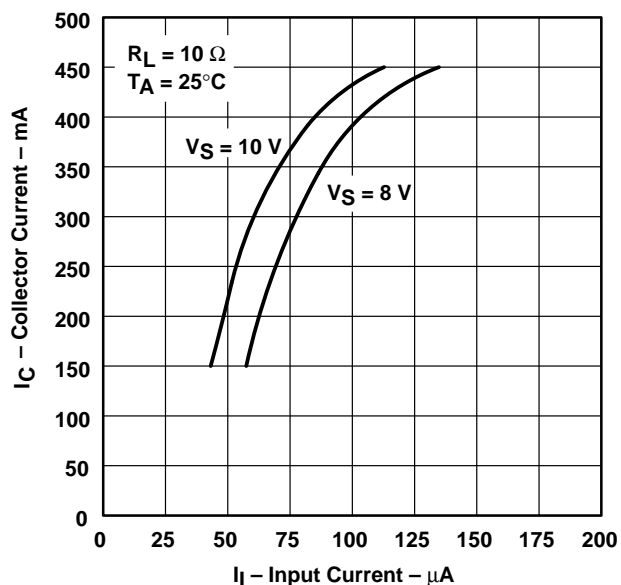


Figure 13

THERMAL INFORMATION

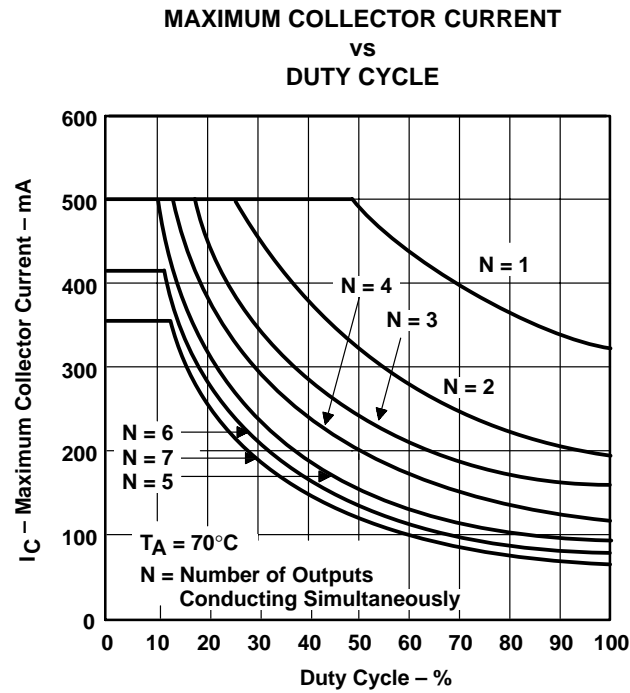


Figure 14

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APPLICATION INFORMATION

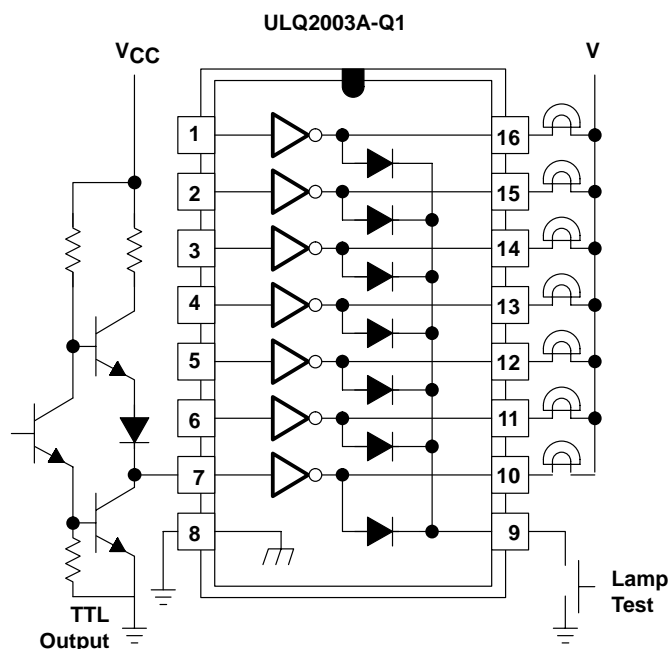


Figure 15. TTL to Load

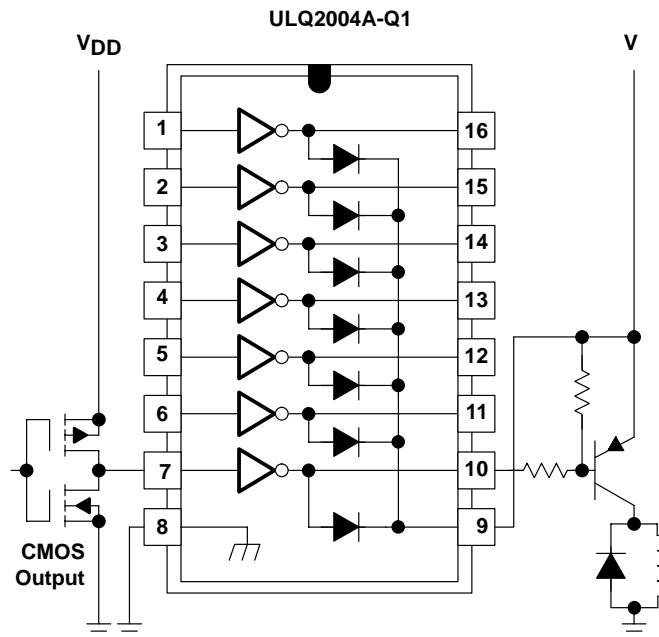


Figure 16. Buffer for Higher Current Loads

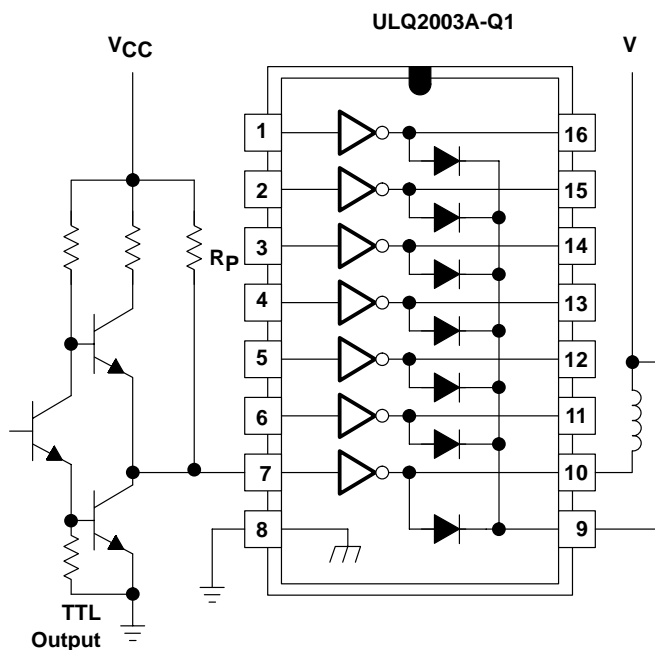


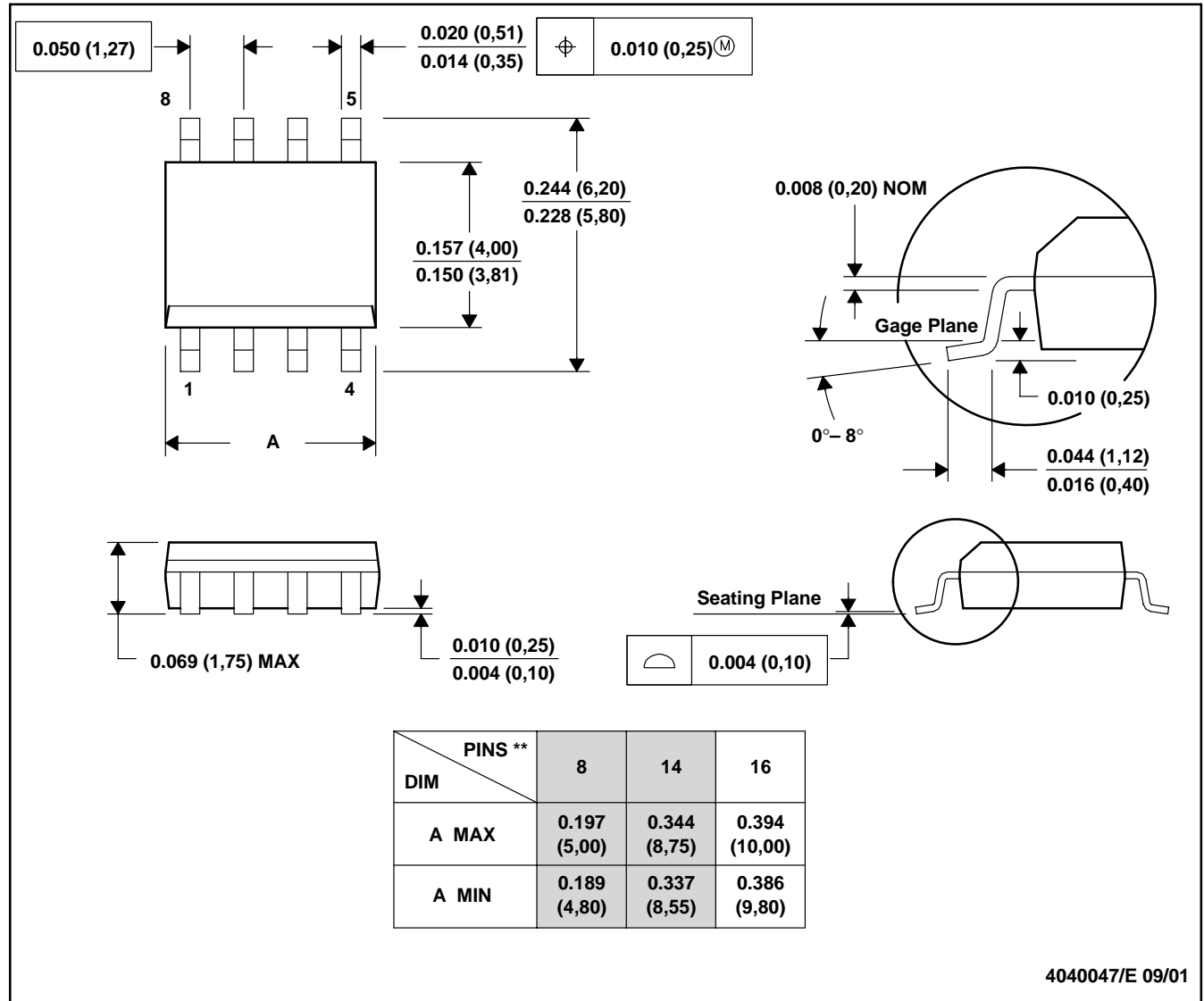
Figure 17. Use of Pullup Resistors
to Increase Drive Current

MECHANICAL DATA

D (R-PDSO-G)**

PLASTIC SMALL-OUTLINE PACKAGE

8 PINS SHOWN

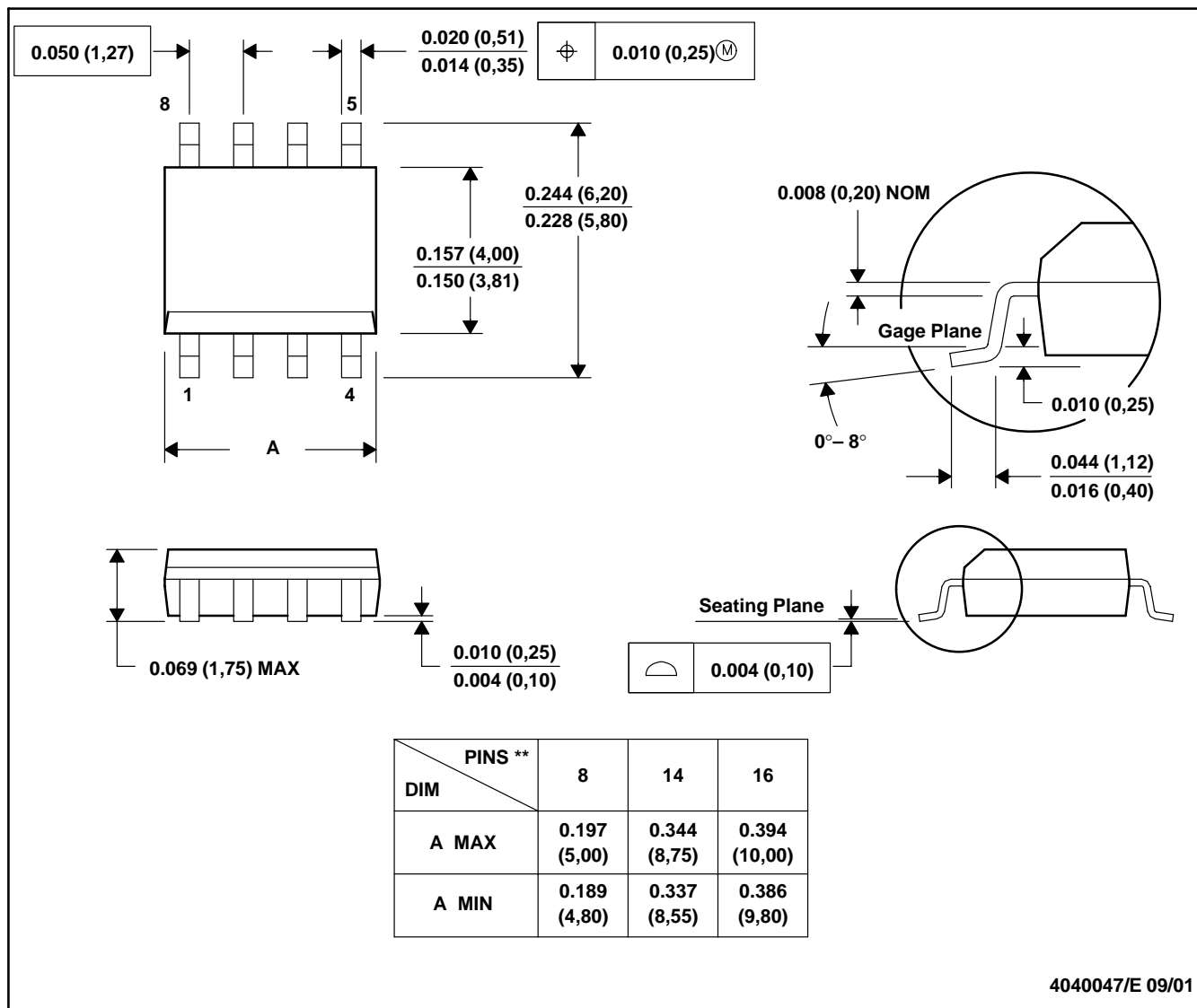


- NOTES: A. All linear dimensions are in inches (millimeters).
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
 D. Falls within JEDEC MS-012

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

8 PINS SHOWN



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